Search	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/619,468	CHIEN, HUI-CHUEH	
Examiner	Art Unit	
Rvan Lepisto	2883	

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INTERFERENCE SEARCHED		
Subclass	Date	Examiner
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	Subclass	Subclass Date

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
See EAST search history	6/13/2005	RAL	
See PALM inventorship search			
See IEEEXplorer, INSPEC, IP.com and SPIE non-patent literature searches			
Consulted Brian Healy concerning allowable subject matter	1/27/2005	1	